



PATENT
Customer No. 22,852
Attorney Docket No. 7241-16

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)
)
Nobuya Kitaguchi et al.) Group Art Unit: 1743
)
Application No.: 10/031,073) Examiner: Monique T. Cole
)
Filed: January 15, 2002)
)
For: Method for Measuring Substance) Confirmation No.: 3837
and Measurement Reagent Used)
in the Same)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT

Enclosed for the consideration of the Examiner in connection with the prosecution of this case is a copy of each of three articles listed on the attached Form PTO/SB/08 relating to thermal lens microscopy.

Enclosed is a check for \$180 to enable the Examiner to consider these articles at this time. If any additional fee is required, please charge it to our deposit account 06-0916.

06/09/2005 CNGUYEN 00000017 10031073

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180.00 OP

Dated: June 8, 2005

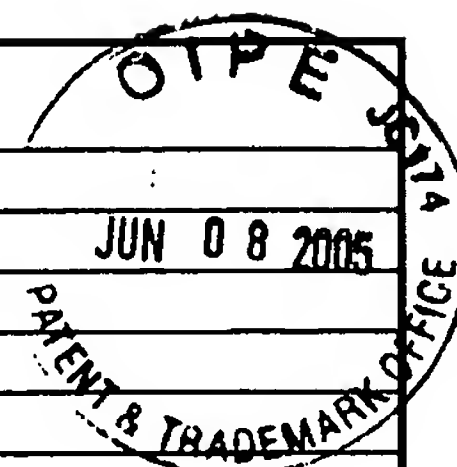
Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW,
GARRETT & DUNNER, L.L.P.

By: 

Arthur S. Garrett
Reg. No. 20,338

IDS Form PTO/SB/08: Substitute for form 1449A/PTO <div style="text-align: center; font-weight: bold; font-size: 1.2em;"> INFORMATION DISCLOSURE STATEMENT BY APPLICANT </div> <div style="text-align: center; font-size: 0.8em;"> <i>(Use as many sheets as necessary)</i> </div>			Complete if Known		
			Application Number	10/031,073	
			Filing Date	January 15, 2002	
			First Named Inventor	Nobuya Kitaguchi et al.	
			Art Unit	1743	
			Examiner Name	Monique T. Cole	
			Attorney Docket Number	7241-16	
Sheet	1	of	2		



U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS					
Examiner Initials	Cite No. ¹	Document Number	Issue or Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
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Note: Submission of copies of U.S. Patents and published U.S. Patent Applications is not required.

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation ⁶
		Country Code ³ Number ⁴ Kind Code ⁵ (if known)				

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation ⁶
		TAKEHIKO KITAMORI ET AL, "Thermal Lens Microscopy and Microchip Chemistry," Analytical Chemistry, February 1, 2004, pp. 53A-60A.	
		KENJI UCHIYAMA ET AL., "Thermal Lens Microscope," Jpn. J. Appl. Phys. Vol. 39 (2000) pp. 5316-5322.	
		MASAAKI HARADA ET AL., "Photothermal Microscopy with Excitation and Probe Beams Coaxial under the Microscope and Its Application to Microparticle Analysis," Anal. Chem. 1993, 65, 2938-2940.	

Examiner Signature		Date Considered	
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.
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